

# LOW SKEW, 1-TO-6, CRYSTAL/LVCMOS/DIFFERENTIAL-TO-3.3V, 2.5V LVPECL FANOUT BUFFER

ICS8536-01

# GENERAL DESCRIPTION



The ICS8536-01 is a low skew, high performance 1-to-6 Selectable Crystal, Single-Ended, or Differential Input-to-3.3V, 2.5V LVPECL Fanout Buffer and a member of the HiPerClockS™ family of High Performance Clock Solutions from IDT. The

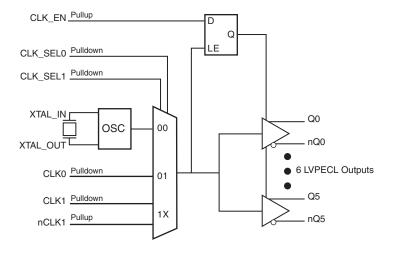
ICS8536-01 has selectable crystal, single ended or differential clock inputs. The single ended clock input accepts LVCMOS or LVTTL input levels and translates them to LVPECL levels. The CLK1, nCLK1 pair can accept most standard differential input levels. The output enable is internally synchronized to eliminate runt pulses on the outputs during asynchronous assertion/deassertion of the clock enable pin.

Guaranteed output and part-to-part skew characteristics make the ICS8536-01 ideal for those applications demanding well defined performance and repeatability.

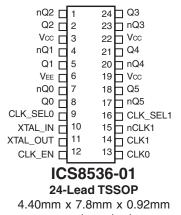
# **FEATURES**

- Six 3.3V, 2.5V LVPECL outputs
- Selectable crystal oscillator, differential CLK1/nCLK1 pair or LVCMOS/LVTTL clock input
- CLK1/nCLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- · Maximum output frequency: 266MHz
- Crystal frequency range: 14MHz 40MHz
- Output skew: 35ps (typical)
- Part-to-part skew: TBD
- Additive phase jitter, RMS: 0.19ps (typical)
- Propagation delay: 2.11ns (typical), CLK1/nCLK1
- Full 3.3V or 2.5V supply mode
- 0°C to 70°C ambient operating temperature
- · Industrial temperature information available upon request
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

# BLOCK DIAGRAM



# PIN ASSIGNMENT



package body **G Package** Top View

The Preliminary Information presented herein represents a product in pre-production. The noted characteristics are based on initial product characterization and/or qualification. Integrated Device Technology, Incorporated (IDT) reserves the right to change any circuitry or specifications without notice.

TABLE 1. PIN DESCRIPTIONS

Number	Name	Ty	/ре	Description
1, 2	nQ2, Q2	Output		Differential output pair. LVPECL interface levels.
3, 19, 22	V <sub>cc</sub>	Power		Power supply pins.
4, 5	nQ1, Q1	Output		Differential output pair. LVPECL interface levels.
6	$V_{EE}$	Power		Negative supply pins.
7, 8	nQ0, Q0	Ouput		Differential output pair. LVPECL interface levels.
9, 16	CLK_SEL0, CLK_SEL1	Input	Pulldown	Clock select pins. LVCMOS/LVTTL interface levels. See Table 3B.
10, 11	XTAL_IN, XTAL_OUT	Input		Parallel resonant crystal interface. XTAL_OUT is the output, XTAL_IN is the input.
12	CLK_EN	Input	Pullup	Synchronizing clock enable. When HIGH, clock outputs follow clock input. When LOW, the outputs are disabled. LVCMOS / LVTTL interface levels. See Table 3A.
13	CLK0	Input	Pulldown	LVCMOS/LVTTL clock input.
14	CLK1	Input	Pulldown	Non-inverting differential clock input.
15	nCLK1	Input	Pullup	Inverting differential clock input.
17, 18	nQ5, Q5	Output		Differential output pair. LVPECL interface levels.
20, 21	nQ4, Q4	Output		Differential output pair. LVPECL interface levels.
23, 24	nQ3, Q3	Output		Differential output pair. LVPECL interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ
R <sub>PULLUP</sub>	Input Pulup Resistor			51		kΩ

TABLE 3A. CONTROL INPUT FUNCTION TABLE

	I	Out	puts		
CLK_EN	CLK_EN CLK_SEL1 CLK_SEL0 Selected Source		Q0:Q5	nQ0:nQ5	
0	0	0	XTAL	Disabled	Disabled
0	0	1	CLK0	Disabled	Disabled
0	1	Х	CLK1/nCLK1	Disabled	Disabled
1	0	0	XTAL	Enabled	Enabled
1	0	1	CLK0	Enabled	Enabled
1	1	X	CLK1/nCLK1	Enabled	Enabled

After CLK\_EN switches, the clock outputs are disabled or enabled following a rising and falling input clock edge as show in *Figure 1*.

In the active mode, the state of the outputs are a function of the selected clock input as described in Table 3B.

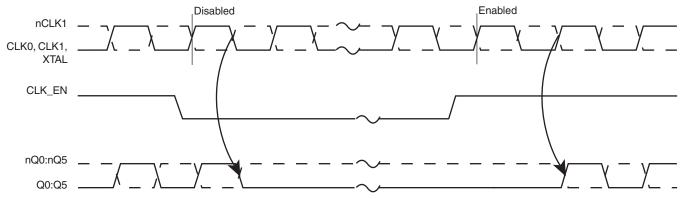


FIGURE 1. CLK\_EN TIMING DIAGRAM

# LOW SKEW, 1-TO-6, CRYSTAL/LVCMOS/DIFFERENTIAL-TO-3.3V, 2.5V LVPECL FANOUT BUFFER

#### **ABSOLUTE MAXIMUM RATINGS**

Supply Voltage,  $V_{CC}$  4.6V

Inputs,  $V_1$  -0.5V to  $V_{cc}$  + 0.5V

Outputs, I<sub>o</sub>

Continuous Current 50mA Surge Current 100mA

Package Thermal Impedance,  $\theta_{JA}$  70°C/W (0 mps) Storage Temperature,  $T_{STG}$  -65°C to 150°C NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Table 4A. Power Supply DC Characteristics,  $V_{cc} = 3.3V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>cc</sub>	Core Supply Voltage		3.135	3.3	3.465	V
I <sub>EE</sub>	Power Supply Current			70		mA

Table 4B. Power Supply DC Characteristics,  $V_{CC} = 2.5V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>cc</sub>	Core Supply Voltage		2.375	2.5	2.625	V
I <sub>EE</sub>	Power Supply Current			60		mA

Table 4C. LVCMOS / LVTTL DC Characteristics,  $V_{CC} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V	Input High Vol	togo	V <sub>CC</sub> = 3.3V	2		$V_{cc} + 0.3$	V
V <sub>IH</sub>	Input High Vol	lage	V <sub>CC</sub> = 2.5V	1.7		$V_{cc} + 0.3$	V
V	Input Low Volt	tago	V <sub>CC</sub> = 3.3V	-0.3		0.8	V
V <sub>IL</sub> Input Low Vo	Input Low von	age	V <sub>CC</sub> = 2.5V	-0.3		0.7	V
I <sub>IH</sub>	Input	CLK0, CLK_SEL0:1	$V_{CC} = V_{IN} = 3.465V \text{ or } 2.625V$			150	μΑ
	High Current	CLK_EN	$V_{CC} = V_{IN} = 3.465 V \text{ or } 2.625 V$			5	μΑ
Input Low Current		CLK0, CLK_SEL0:1	$V_{CC} = 3.465V \text{ or } 2.625V, V_{IN} = 0V$	-5			μΑ
IL	Low Current CLK_EN		$V_{CC} = 3.465V \text{ or } 2.625V, V_{IN} = 0V$	-150			μΑ

Table 4D. Differential DC Characteristics,  $V_{cc} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ , Ta =  $0^{\circ}$ C to  $70^{\circ}$ C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
	la sant I limb O		$V_{CC} = V_{IN} = 3.465V \text{ or } 2.625V$			5	μΑ
'IH	Input High Current	CLK1	$V_{CC} = V_{IN} = 3.465V$			150	μΑ
	Input Low Current	nCLK1	$V_{CC} = 3.465V \text{ or } 2.625V, V_{IN} = 0V$	-150			μΑ
' <sub>IL</sub>	Imput Low Current	CLK1	$V_{CC} = 3.465V \text{ or } 2.625V, V_{IN} = 0V$	-5			μΑ
V <sub>PP</sub>	Peak-to-Peak Input Voltage			0.15		1.3	V
V <sub>CMR</sub>	Common Mode Input Voltage; NOTE 1, 2			V <sub>EE</sub> + 0.5		V <sub>cc</sub> - 0.85	V

NOTE 1: For single ended applications the maximum input voltage for CLK1, nCLK1 is  $V_{\rm CC}$  + 0.3V.

NOTE 2: Common mode voltage is defined as  $V_{\rm IH}$ .

Table 4E. LVPECL DC Characteristics,  $V_{CC} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ , Ta = 0°C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OH</sub>	Output High Voltage; NOTE 1		V <sub>cc</sub> - 1.4		V <sub>cc</sub> - 0.9	V
V <sub>OL</sub>	Output Low Voltage; NOTE 1		V <sub>cco</sub> - 2.0		V <sub>cc</sub> - 1.7	V
V <sub>SWING</sub>	Peak-to-Peak Output Voltage Swing		0.6		1.0	V

NOTE 1: Outputs terminated with 50  $\!\Omega$  to V  $_{\!CC}$  - 2V.

TABLE 5. CRYSTAL CHARACTERISTICS

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fu	ındamenta	al	
Frequency		14		40	MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF
Drive Level				1	mW

NOTE: Characterized using an 18pF parallel resonant crystal.

Table 6A. AC Characteristics,  $V_{cc} = 3.3V \pm 5\%$ , Ta = 0°C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency					266	MHz
+	Propagation Delay,	CLK1, nCLK1			2.11		ns
PD	NOTE1A, 1B	CLK0			1.75		ns
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 2		155.52MHz, Integration Range: 12kHz - 20MHz		0.19		ps
tsk(o)	Output Skew; NOTE	3, 5			35		ps
tsk(pp)	Part-to-Part Skew; N	IOTE 4, 5			TBD		ps
$t_R / t_F$	Output Rise/Fall Time		20% to 80%		400		ps
odc	Output Duty Cycle				50		%
MLIV	MUX Isolation	NOTE 6A	f = 150MHz		-76		dB
MUX_ISOLATION	IVIOA ISOIALIOIT	NOTE 6B	f = 250MHz		-75		dB

All parameters measured at  $f_{\text{MAX}}$  unless noted otherwise.

The cycle-to-cycle jitter on the input will equal the jitter on the output. The part does not add jitter

NOTE 1A: Measured from the differential input crossing point to the differential output crossing point.

NOTE 1B: Measured from V<sub>cc</sub>/2 input crossing point to the differential output crossing point.

NOTE 2: Driving only one input clock.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at the output differential cross points.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential cross points.

NOTE 5: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 6A: XTAL's sensitivity measured while differential CLK1/nCLK1 driving data at 150MHz.

NOTE 6B: Single-ended CLK0's sensitivity measured while differential CLK1/nCLK1 driving data at 250MHz.

Table 6B. AC Characteristics,  $V_{cc} = 2.5V \pm 5\%$ , Ta = 0°C to 70°C

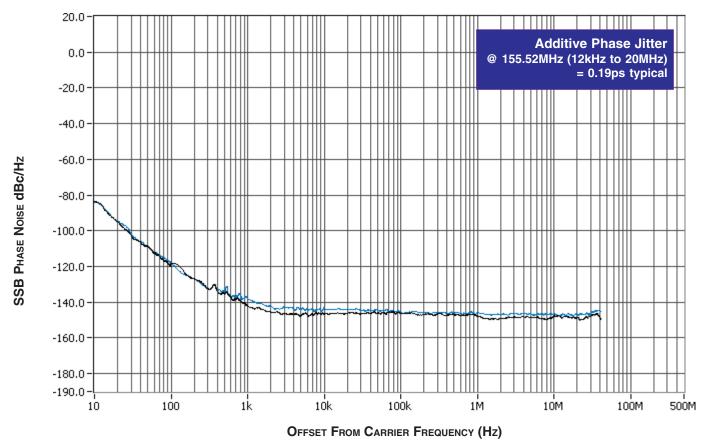
Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency					266	MHz
	Propagation Delay,	CLK1, nCLK1			2.11		ns
L <sub>PD</sub>	NOTE1A, 1B	CLK0			1.75		ns
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 2		155.52MHz, Integration Range: 12kHz - 20MHz		0.17		ps
tsk(o)	Output Skew; NOTE	3, 5			35		ps
tsk(pp)	Part-to-Part Skew; N	IOTE 4, 5			TBD		ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Tim	пе	20% to 80%		400		ps
odc	Output Duty Cycle				50		%
MILIV	MUV loolation	NOTE 6A	f = 150MHz;		-74		dB
MUX_ISOLATION	MUX Isolation NOTE 6B		f = 250MHz		-59		dB

See notes above in Table 6A.

# **ADDITIVE PHASE JITTER**

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise*. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz

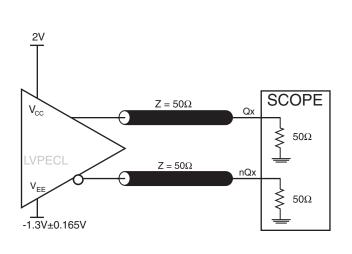
band to the power in the fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.

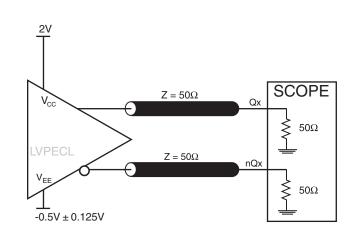


As with most timing specifications, phase noise measurements have issues. The primary issue relates to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device. This is illustrated above. The device

meets the noise floor of what is shown, but can actually be lower. The phase noise is dependant on the input source and measurement equipment.

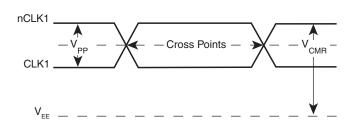
# PARAMETER MEASUREMENT INFORMATION



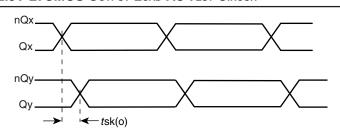


## 3.3V LVPECL OUTPUT LOAD AC TEST CIRCUIT

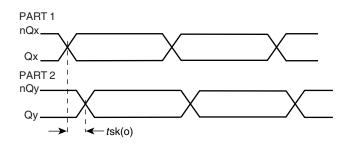




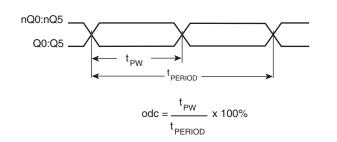
# 2.5V LVCMOS OUTPUT LOAD AC TEST CIRCUIT



# DIFFERENTIAL INPUT LEVELS

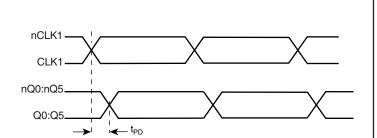


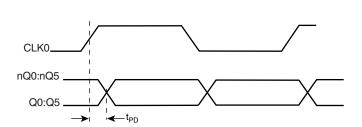
# **O**UTPUT **S**KEW



## PART-TO-PART SKEW

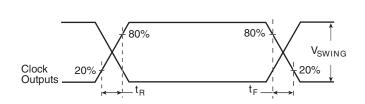
## OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD





# PROPAGATION DELAY (DIFFERENTIAL INPUT)

# PROPAGATION DELAY (LVCMOS INPUT)



## **OUTPUT RISE/FALL TIME**

# **APPLICATION INFORMATION**

#### WIRING THE DIFFERENTIAL INPUT TO ACCEPT SINGLE ENDED LEVELS

*Figure 1* shows how the differential input can be wired to accept single ended levels. The reference voltage  $V_REF = V_{\infty}/2$  is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio

of R1 and R2 might need to be adjusted to position the V\_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and V $_{cc}$  = 3.3V, V\_REF should be 1.25V and R2/R1 = 0.609.

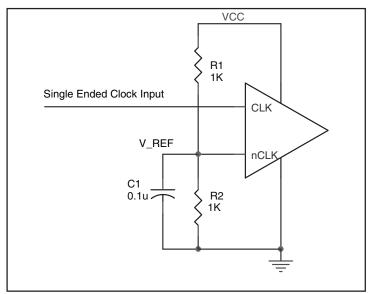


FIGURE 1. SINGLE ENDED SIGNAL DRIVING DIFFERENTIAL INPUT

# **CRYSTAL INPUT INTERFACE**

The ICS8536-01 has been characterized with 18pF parallel resonant crystals. The capacitor values shown in *Figure 2* below

were determined using an 18pF parallel resonant crystal and were chosen to minimize the ppm error.

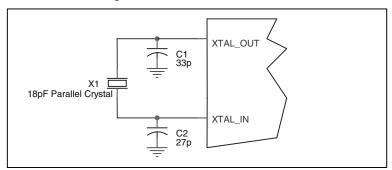


FIGURE 2. CRYSTAL INPUT INTERFACE

## LVCMOS TO XTAL INTERFACE

The XTAL\_IN input can accept a single-ended LVCMOS signal through an AC coupling capacitor. A general interface diagram is shown in *Figure 3*. The XTAL\_OUT pin can be left floating. The input edge rate can be as slow as 10ns. For LVCMOS inputs, it is recommended that the amplitude be reduced from full swing to half swing in order to prevent signal interference with the power rail and to reduce noise. This configuration requires that the output

impedance of the driver (Ro) plus the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First, R1 and R2 in parallel should equal the transmission line impedance. For most  $50\Omega$  applications, R1 and R2 can be  $100\Omega$ . This can also be accomplished by removing R1 and making R2  $50\Omega$ .

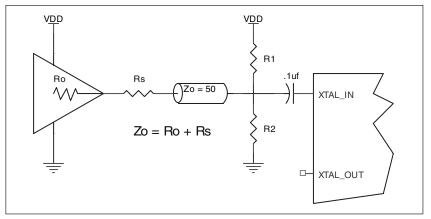


FIGURE 3. GENERAL DIAGRAM FOR LVCMOS DRIVER TO XTAL INPUT INTERFACE

#### RECOMMENDATIONS FOR UNUSED INPUT AND OUTPUT PINS

#### INPUTS:

#### CRYSTAL INPUT:

For applications not requiring the use of the crystal oscillator input, both XTAL\_IN and XTAL\_OUT can be left floating. Though not required, but for additional protection, a  $1 k\Omega$  resistor can be tied from XTAL\_IN to ground.

#### **CLK INPUT:**

For applications not requiring the use of the test clock, it can be left floating. Though not required, but for additional protection, a  $1k\Omega$  resistor can be tied from the CLK input to ground.

#### **CLK/nCLK INPUT:**

For applications not requiring the use of the differential input, both CLK and nCLK can be left floating. Though not required, but for additional protection, a  $1k\Omega$  resistor can be tied from CLK to ground.

#### LVCMOS CONTROL PINS:

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

#### **OUTPUTS:**

# LVPECL OUTPUT

All unused LVPECL outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

#### **TERMINATION FOR LVPECL OUTPUTS**

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

FOUT and nFOUT are low impedance follower outputs that generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to

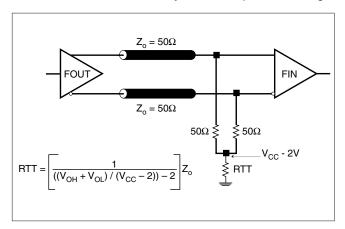


FIGURE 4A. LVPECL OUTPUT TERMINATION

drive  $50\Omega$  transmission lines. Matched impedance techniques should be used to maximize operating frequency and minimize signal distortion. *Figures 4A and 4B* show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

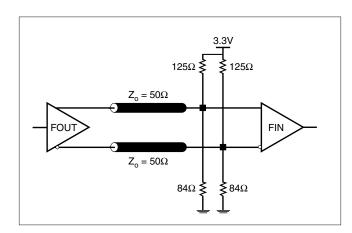


FIGURE 4B. LVPECL OUTPUT TERMINATION

# **TERMINATION FOR 2.5V LVPECL OUTPUTS**

Figure 5A and Figure 5B show examples of termination for 2.5V LVPECL driver. These terminations are equivalent to terminating  $50\Omega$  to  $V_{cc}$  - 2V. For  $V_{cc}$  = 2.5V, the  $V_{cc}$  - 2V is very close to ground

level. The R3 in Figure 5B can be eliminated and the termination is shown in *Figure 5C*.

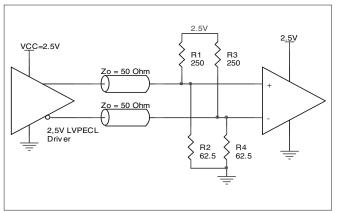


FIGURE 5A. 2.5V LVPECL DRIVER TERMINATION EXAMPLE

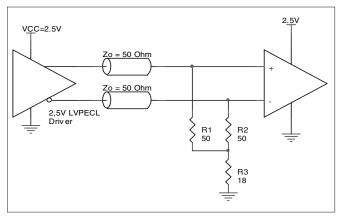


FIGURE 5B. 2.5V LVPECL DRIVER TERMINATION EXAMPLE

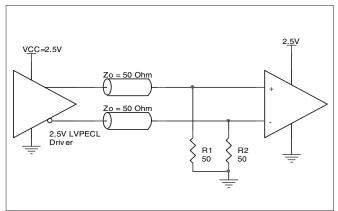


FIGURE 5C. 2.5V LVPECL TERMINATION EXAMPLE

# POWER CONSIDERATIONS

This section provides information on power dissipation and junction temperature for the ICS8536-01. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS8536-01 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{cc} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

**NOTE:** Please refer to Section 3 for details on calculating power dissipated in the load.

- Power (core)<sub>MAX</sub> = V<sub>CC MAX</sub> \* I<sub>EE MAX</sub> = 3.465V \* 70mA = 242.55mW
- Power (outputs)<sub>MAX</sub> = 30mW/Loaded Output pair
   If all outputs are loaded, the total power is 6 \* 30mW = 180mW

Total Power  $_{\text{MAX}}$  (3.465V, with all outputs switching) = 242.55mW + 180mW = 422.6mW

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS™ devices is 125°C.

The equation for Tj is as follows: Tj =  $\theta_{La}$  \* Pd\_total + T<sub>a</sub>

Tj = Junction Temperature

 $\theta_{\text{\tiny IA}}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

T<sub>A</sub> = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{\text{\tiny M}}$  must be used. Assuming a moderate air flow of 1 meter per second and a multi-layer board, the appropriate value is 65°C/W per Table 7 below.

Therefore, Ti for an ambient temperature of 70°C with all outputs switching is:

 $70^{\circ}\text{C} + 0.423\text{W} * 65^{\circ}\text{C/W} = 97.5^{\circ}\text{C}$ . This is well below the limit of  $125^{\circ}\text{C}$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow, and the type of board (single layer or multi-layer).

# Table 7. Thermal Resistance $\theta_{_{JA}}$ for 24-pin TSSOP, Forced Convection

# $\theta_{_{JA}}$ by Velocity (Meters per Second)

Multi-Layer PCB, JEDEC Standard Test Boards 70°C/W 65°C/W

2.5

62°C/W

#### 3. Calculations and Equations.

The purpose of this section is to derive the power dissipated into the load.

LVPECL output driver circuit and termination are shown in Figure 6.

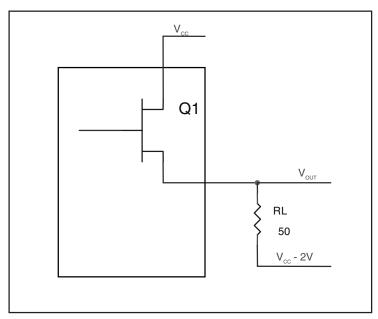


FIGURE 6. LVPECL DRIVER CIRCUIT AND TERMINATION

To calculate worst case power dissipation into the load, use the following equations which assume a  $50\Omega$  load, and a termination voltage of  $V_{\infty}$  - 2V.

• For logic high, 
$$V_{OUT} = V_{OH MAX} = V_{CC MAX} - 0.9V$$

$$(V_{CC MAX} - V_{OH MAX}) = 0.9V$$

• For logic low,  $V_{OUT} = V_{OL\_MAX} = V_{CC\_MAX} - 1.7V$ 

$$(V_{CC,MAX} - V_{OL,MAX}) = 1.7V$$

Pd\_H is power dissipation when the output drives high.

Pd\_L is the power dissipation when the output drives low.

$$Pd\_H = [(V_{\text{OH\_MAX}} - (V_{\text{CC\_MAX}} - 2V))/R] * (V_{\text{CC\_MAX}} - V_{\text{OH\_MAX}}) = [(2V - (V_{\text{CC\_MAX}} - V_{\text{OH\_MAX}}))/R] * (V_{\text{CC\_MAX}} - V_{\text{OH\_MAX}}) = [(2V - 0.9V)/50\Omega] * 0.9V = \textbf{19.8mW}$$

$$Pd\_L = [(V_{\text{\tiny OL\_MAX}} - (V_{\text{\tiny CC\_MAX}} - 2V))/R_{\text{\tiny L}}] * (V_{\text{\tiny CC\_MAX}} - V_{\text{\tiny OL\_MAX}}) = [(2V - (V_{\text{\tiny CC\_MAX}} - V_{\text{\tiny OL\_MAX}}))/R_{\text{\tiny L}}] * (V_{\text{\tiny CC\_MAX}} - V_{\text{\tiny OL\_MAX}}) = [(2V - 1.7V)/50\Omega] * 1.7V = \textbf{10.2mW}$$

Total Power Dissipation per output pair = Pd\_H + Pd\_L = 30mW

# RELIABILITY INFORMATION

Table 8.  $\theta_{_{JA}} vs.$  Air Flow Table for 24 Lead TSSOP

θ<sub>JA</sub> by Velocity (Meters per Second)

0 1 2.5

Multi-Layer PCB, JEDEC Standard Test Boards 70°C/W 65°C/W 62°C/W

#### **TRANSISTOR COUNT**

The transistor count for ICS8536-01 is: 513

## PACKAGE OUTLINE - G SUFFIX FOR 24 LEAD TSSOP

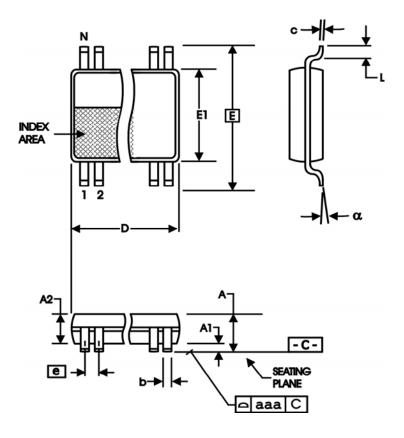


TABLE 9. PACKAGE DIMENSIONS

SYMBOL	Millin	neters	
STWIBOL	Minimum	Maximum	
N	24		
А		1.20	
A1	0.05	0.15	
A2	0.80	1.05	
b	0.19	0.30	
С	0.09	0.20	
D	7.70	7.90	
E	6.40 E	BASIC	
E1	4.30	4.50	
е	0.65 E	BASIC	
L	0.45	0.75	
α	0°	8°	
aaa		0.10	

Reference Document: JEDEC Publication 95, MO-153

# LOW SKEW, 1-TO-6, CRYSTAL/LVCMOS/DIFFERENTIAL-TO-3.3V, 2.5V LVPECL FANOUT BUFFER

TABLE 10. ORDERING INFORMATION

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
ICS8536AG-01	ICS8536AG-01	24 Lead TSSOP	tube	0°C to 70°C
ICS8536AG-01T	ICS8536AG-01	24 Lead TSSOP	2500 tape & reel	0°C to 70°C
ICS8536AG-01LF	ICS8536AG-01L	24 Lead "Lead-Free" TSSOP	tube	0°C to 70°C
ICS8536AG-01LFT	ICS8536AG-01L	24 Lead "Lead-Free" TSSOP	2500 tape & reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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